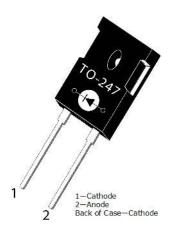


# **APT100S20BG High-Voltage Schottky Diode**

### 1 Product Overview

This section outlines the product overview for the APT100S20BG device.



### 1.1 Features

The following are key features of the APT100S20BG device:

- Low forward voltage
- Low leakage current
- Ultrafast reverse recovery
- Avalanche energy rated
- RoHS compliant

#### 1.2 Benefits

The following are benefits of the APT100S20BG device:

- High switching frequency
- Low switching losses
- Low noise (EMI) switching
- Higher reliability systems
- Increased system power density

### 1.3 Applications

The APT100S20BG device is designed for the following applications:

- Power supply and distribution
- Switch-mode power supply
- Inverter, converter, and industrial motor drivers
- High-speed rectifiers



# **2** Device Specifications

This section shows the device specifications for the APT100S20BG device.

## 2.1 Absolute Maximum Ratings

The following table shows the absolute maximum ratings for the APT100S20BG device.  $T_1 = 25$  °C unless otherwise specified.

Table 1 • Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
VR	Maximum DC reverse voltage	200	V
VRRM	Maximum peak repetitive reverse voltage		
VRWM	Maximum working peak reverse voltage		
IF(AV)	Maximum average forward current (Tc = 125 °C, duty cycle = 0.5)	120	Α
IF(RMS)	RMS forward current	318	<del>_</del>
IFSM	Non-repetitive forward surge current (T <sub>J</sub> = 45 °C, 8.3 ms)	1000	_
Tı, Tstg	Operating and storage temperature range	-55 to 150	°C
TL	Lead temperature for 10 seconds	300	_

The following table shows the thermal and mechanical characteristics of the APT100S20BG device.

Table 2 • Thermal and Mechanical Characteristics

Symbol	Characteristic/Test Conditions	Min	Тур	Max	Unit
Rejc	Junction-to-case thermal resistance			0.18	°C/W
Wt	Package weight		0.22		OZ
			6.2		g
	Maximum mounting torque, 6-32 or M3 screw			10	lbf-in
				1.1	N-m

## 2.2 Electrical Performance

The following table shows the static characteristics of the APT100S20BG device.  $T_1 = 25$  °C unless otherwise specified.

**Table 3 • Static Characteristics** 

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
VF	Forward voltage	I <sub>F</sub> = 100 A		0.89	0.95	
		I <sub>F</sub> = 200 A		1.06		– V
		I <sub>F</sub> = 100 A, T <sub>J</sub> = 125 °C		0.76		=
Irм	Maximum reverse leakage current	V <sub>R</sub> = 200 V			2	mA
		V <sub>R</sub> = 200 V, T <sub>J</sub> = 125 °C			40	=
Cı	Junction capacitance	V <sub>R</sub> = 200 V		470		pF



The following table shows the dynamic characteristics of the APT100S20BG device.

**Table 4 • Dynamic Characteristics** 

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
trr	Reverse recovery time	$I_F = 100 \text{ A}$ $di_F/dt = -200 \text{ A}/\mu \text{s}$ $V_R = 133 \text{ V}$ $T_J = 25 \text{ °C}$		70		ns
Qrr	Reverse recovery charge		-	230		nC
IRRM	Maximum reverse recovery current			6		Α
trr	Reverse recovery time	$I_F = 100 \text{ A}$ $di_F/dt = -200 \text{ A}/\mu\text{S}$ $V_R = 133 \text{ V}$ $T_J = 125 \text{ °C}$		110		ns
Qrr	Reverse recovery charge			690		nC
IRRM	Maximum reverse recovery current			11		Α
trr	Reverse recovery time	$I_F = 100 \text{ A}$ $di_F/dt = -700 \text{ A/}\mu\text{s}$ $V_R = 133 \text{ V}$ $T_J = 125 \text{ °C}$		95		ns
Qrr	Reverse recovery charge			1750		nC
IRRM	Maximum reverse recovery current			32		Α

# 2.3 Typical Performance Curves

This section shows the typical performance curves for the APT100S20BG device.

Figure 1 • Maximum Transient Thermal Impedance

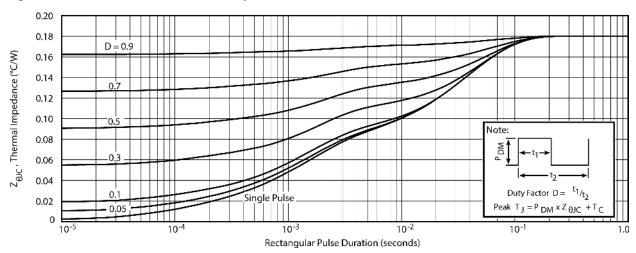




Figure 2 • Forward Current vs. Forward Voltage (V)

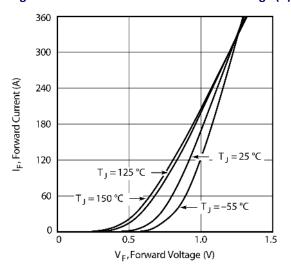


Figure 4 ● Reverse Recovery Charge vs. Current Rate of Change

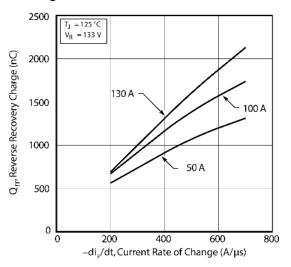


Figure 3 • RRT vs. Current Rate of Change

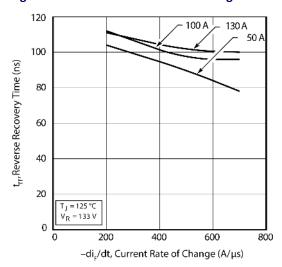


Figure 5 • Reverse Recovery Current vs. Current Rate of Change

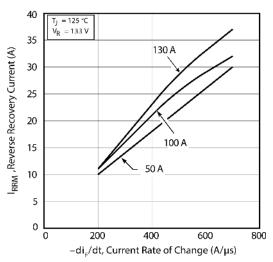




Figure 6 • Dynamic Parameters vs. Junction Temperature

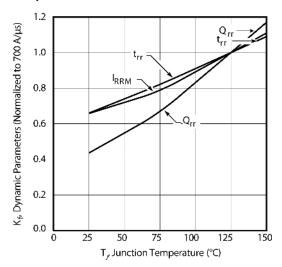


Figure 8 • Junction Capacitance vs. Reverse Voltage

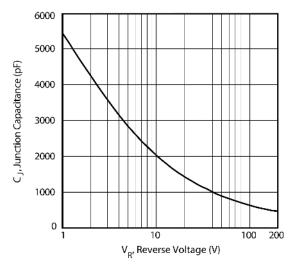


Figure 7 • Maximum Average Forward Current vs. Case Temperature

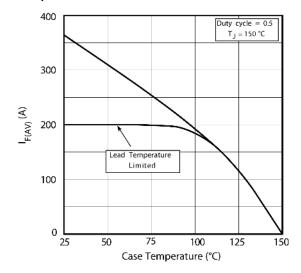
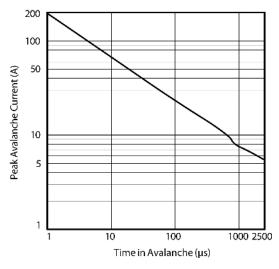


Figure 9 • Single Pulse UIS SOA

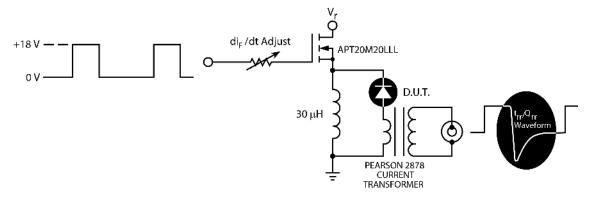




### 2.4 Reverse Recovery Overview

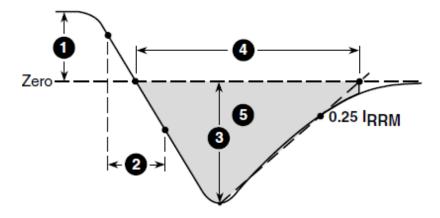
The following illustration shows the diode test circuit for the APT100S20BG device.

Figure 10 • Diode Test Circuit



The following illustration shows the diode reverse recovery waveform and definitions for the APT100S20BG device.

Figure 11 • Diode Reverse Recovery Waveform and Definitions



- 1. IF—Forward conduction current
- 2. di<sub>F</sub>/dt—Rate of diode current change through zero crossing
- 3. IRRM—Maximum reverse recovery current
- 4. trr—Reverse recovery time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through IRRM and 0.25•IRRM passes through zero
- 5. Qrr—Area under the curve defined by IRRM and trr



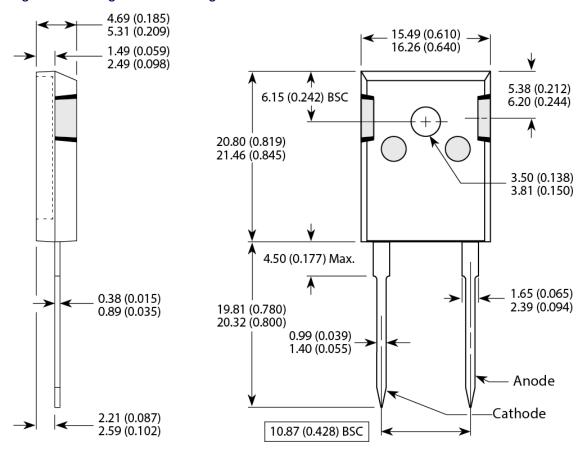
# **3** Package Specification

This section outlines the package specification for the APT100S20BG device.

# 3.1 Package Outline Drawing

The following figure shows the package outline drawing of the APT100S20BG device. Dimensions are in millimeters and (inches).

Figure 12 • Package Outline Drawing







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